

# **HAT3004R**

# Silicon N Channel / P Channel Power MOS FET High Speed Power Switching

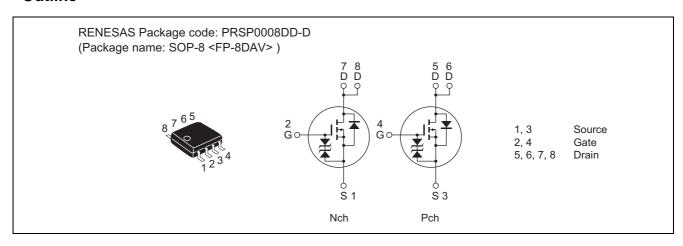
REJ03G1196-1100 (Previous: ADE-208-500I)

> Rev.11.00 Sep 07, 2005

#### **Features**

- Low on-resistance
- Capable of 4 V gate drive
- Low drive current
- High density mounting

#### **Outline**



# **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Value		Unit	
item	Symbol	Nch Pch			
Drain to source voltage	$V_{DSS}$	30	-30	V	
Gate to source voltage	V <sub>GSS</sub>	±20	±20	V	
Drain current	I <sub>D</sub>	5.5	-3.5	A	
Drain peak current	I <sub>D (pulse)</sub> Note 1	44	-28	A	
Body-drain diode reverse drain current	I <sub>DR</sub>	5.5	-3.5	A	
Channel dissipation	Pch Note 2	2		W	
Channel dissipation	Pch Note 3	3		W	
Channel temperature	Tch	150		°C	
Storage temperature	Tstg	-55 to +150		°C	

Notes: 1. PW  $\leq$  10  $\mu$ s, duty cycle  $\leq$  1%

- 2. 1 Drive operation: When using the glass epoxy board (FR4  $40 \times 40 \times 1.6$  mm), PW  $\leq 10$  s
- 3. 2 Drive operation: When using the glass epoxy board (FR4  $40 \times 40 \times 1.6$  mm), PW  $\leq 10$  s

# **Electrical Characteristics**

#### **N** Channel

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	V <sub>(BR) DSS</sub>	30	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V <sub>(BR)</sub> GSS	±20	_	_	V	$I_G = \pm 100 \ \mu A, \ V_{DS} = 0$
Gate to source leak current	I <sub>GSS</sub>	_	_	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	_	_	10	μΑ	$V_{DS} = 30 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	V <sub>GS (off)</sub>	1.0	_	2.0	V	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$
Static drain to source on state resistance	R <sub>DS (on)</sub>	_	0.050	0.065	Ω	$I_D = 3 \text{ A}, V_{GS} = 10 \text{ V}^{\text{Note 4}}$
	R <sub>DS (on)</sub>	_	0.078	0.11	Ω	$I_D = 3 \text{ A}, V_{GS} = 4 \text{ V}^{\text{Note 4}}$
Forward transfer admittance	y <sub>fs</sub>	3.5	5.5	_	S	$I_D = 3 \text{ A}, V_{DS} = 10 \text{ V}^{\text{Note 4}}$
Input capacitance	Ciss	_	310	_	pF	V <sub>DS</sub> = 10 V
Output capacitance	Coss	_	220	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	100	_	pF	f = 1 MHz
Turn-on delay time	t <sub>d (on)</sub>	_	17	_	ns	$V_{GS} = 4 \text{ V}, I_D = 3 \text{ A}$
Rise time	t <sub>r</sub>	_	190	_	ns	$V_{DD} \cong 10 \text{ V}$
Turn-off delay time	t <sub>d (off)</sub>	_	25	_	ns	
Fall time	t <sub>f</sub>	_	60	_	ns	
Body-drain diode forward voltage	$V_{DF}$	_	0.9	1.4	V	$I_F = 5.5 \text{ A}, V_{GS} = 0^{\text{Note 4}}$
Body-drain diode reverse recovery time	t <sub>rr</sub>	_	50	_	ns	$I_F = 5.5 \text{ A}, V_{GS} = 0$
						di <sub>F</sub> /dt = 20 A/μs

Note: 4. Pulse test

# P Channel

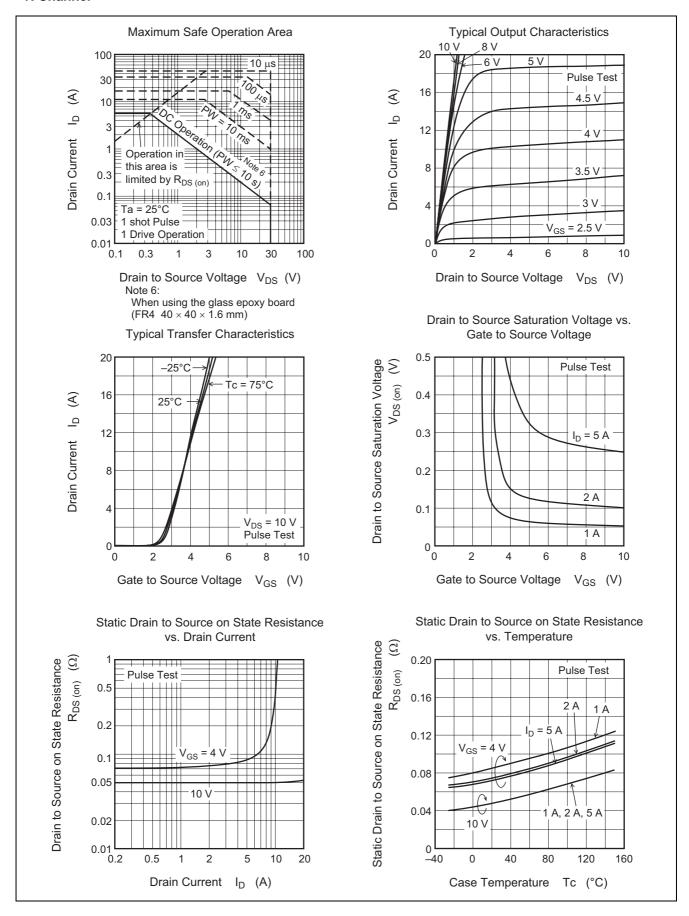
 $(Ta = 25^{\circ}C)$ 

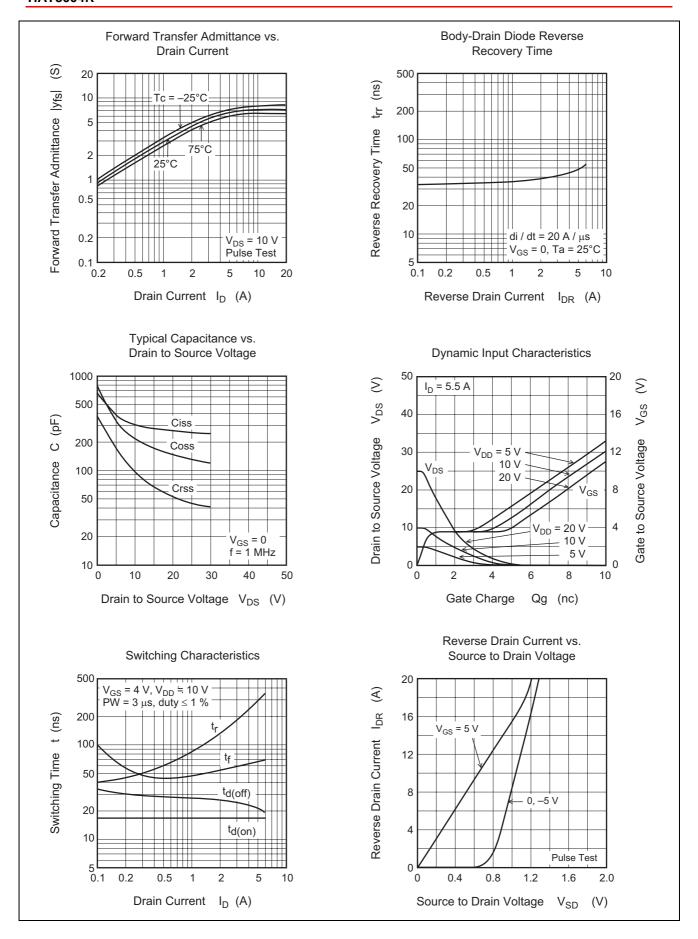
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	V <sub>(BR) DSS</sub>	-30	_	_	V	$I_D = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V <sub>(BR) GSS</sub>	±20	_	_	V	$I_G = \pm 100 \ \mu A, \ V_{DS} = 0$
Gate to source leak current	I <sub>GSS</sub>	_	_	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	_	_	-10	μΑ	$V_{DS} = -30 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	V <sub>GS (off)</sub>	-1.0	_	-2.5	V	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$
Static drain to source on state resistance	R <sub>DS (on)</sub>	_	0.12	0.16	Ω	$I_D = -2 \text{ A}, V_{GS} = -10 \text{ V}^{\text{Note 5}}$
	R <sub>DS (on)</sub>	_	0.20	0.34	Ω	$I_D = -2 \text{ A}, V_{GS} = -4 \text{ V}^{\text{Note 5}}$
Forward transfer admittance	y <sub>fs</sub>	2.5	3.5	_	S	$I_D = -2 \text{ A}, V_{DS} = -10 \text{ V}^{\text{Note 5}}$
Input capacitance	Ciss	_	350	_	pF	V <sub>DS</sub> = -10 V
Output capacitance	Coss	_	230	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	75	_	pF	f = 1 MHz
Turn-on delay time	t <sub>d (on)</sub>	_	18	_	ns	$V_{GS} = -4 \text{ V}, I_D = -2 \text{ A}$
Rise time	t <sub>r</sub>	_	110	_	ns	V <sub>DD</sub> ≅ -10 V
Turn-off delay time	t <sub>d (off)</sub>	_	20	_	ns	
Fall time	t <sub>f</sub>	_	30	_	ns	
Body-drain diode forward voltage	$V_{DF}$	_	-1.0	-1.5	V	$I_F = -3.5 \text{ A}, V_{GS} = 0^{\text{Note 5}}$
Body-drain diode reverse recovery time	t <sub>rr</sub>	_	60	_	ns	$I_F = -3.5 \text{ A}, V_{GS} = 0$
						di <sub>F</sub> /dt = 20 A/μs

Note: 5. Pulse test

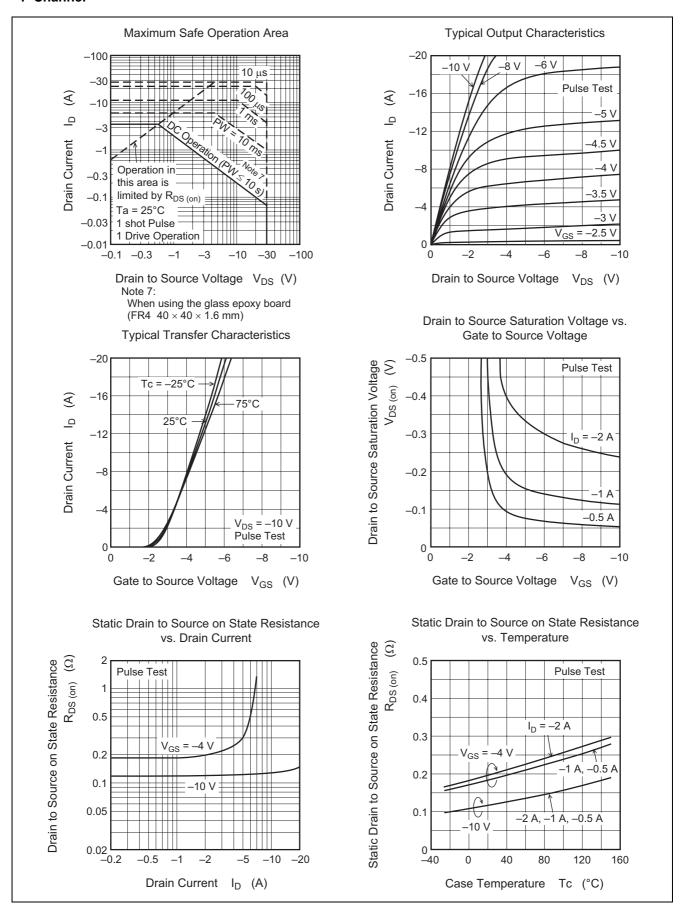
#### **Main Characteristics**

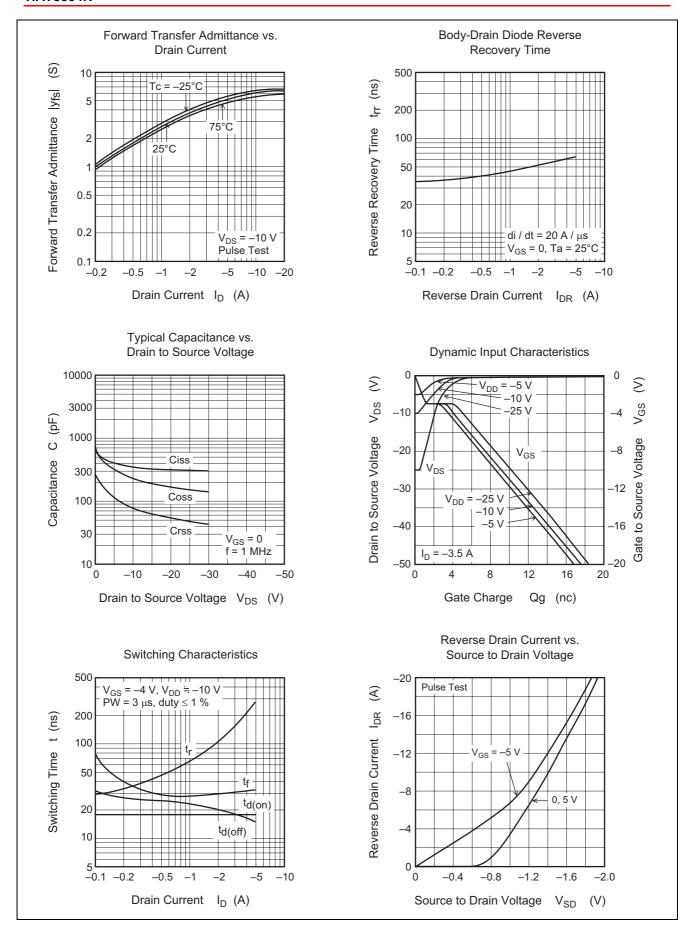
#### **N** Channel



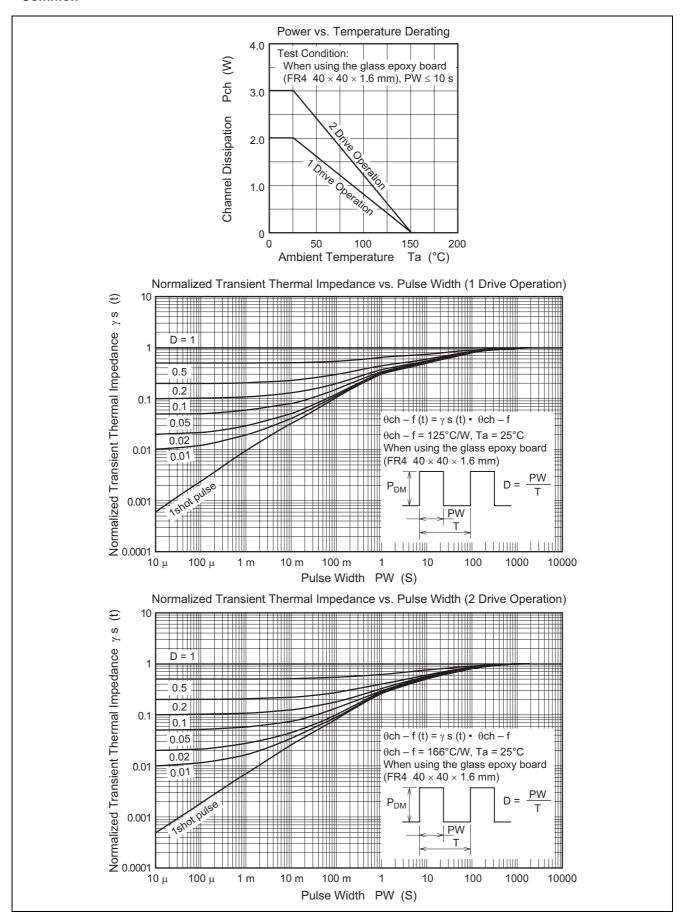


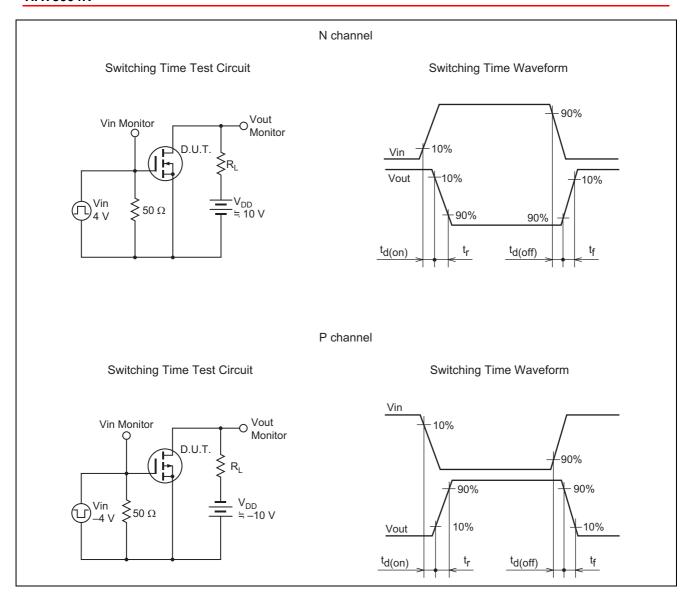
#### P Channel



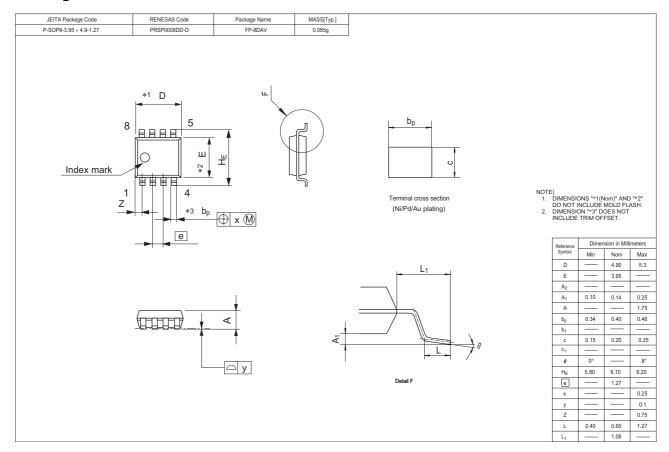


#### Common





# **Package Dimensions**



# **Ordering Information**

Part Name	Quantity	Shipping Container
HAT3004R-EL-E	2500 pcs	Taping

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